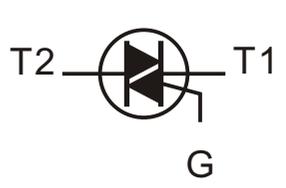
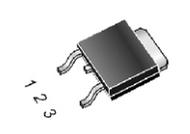


### HAOPIN MICROELECTRONICS CO.,LTD.

#### Description

Passivated high commutation triacs in a plastic envelope intended for use in circuits where high static and dynamic dV/dt and high dI/dt can occur. These devices will commute the full rated ms current at the maximum rated junction temperature without the aid of a snubber.

Symbol		Simplified outline	
		 TO-252	
Pin	Description		
1	Main terminal 1 (T1)		
2	Main terminal 2 (T2)		
3	gate (G)		
TAB	Main terminal 2 (T2)		

#### Applications:

- ◆ Motor control
- ◆ Industrial and domestic lighting
- ◆ Heating
- ◆ Static switching

#### Features

- ◆ Blocking voltage to 800 V
- ◆ On-state RMS current to 8 A

SYMBOL	PARAMETER	Value	Unit
V <sub>DRM</sub>	Repetitive peak off-state voltages	800	V
I <sub>T (RMS)</sub>	RMS on-state current (full sine wave)	8	A
I <sub>TSM</sub>	Non-repetitive peak on-state current (full cycle, T <sub>j</sub> initial=25°C)	84	A

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT
R <sub>th(j-c)</sub>	Junction to case(AC)		-	1.6	-	°C/W
R <sub>th(j-a)</sub>	Junction to ambient		-	70	-	°C/W



# HP8Q80DS

## Three quadrant triacs

HAOPIN MICROELECTRONICS CO.,LTD.

Limiting values in accordance with the Maximum system(IEC 134)

SYMBOL	PARAMETER	CONDITIONS		MIN	Value	UNIT
$V_{DRM}/V_{RRM}$	Repetitive peak off-state Voltages			-	800	V
$I_{T(RMS)}$	RMS on-state current	Full sine wave; $T_c=110^\circ\text{C}$		-	8	A
$I_{TSM}$	Non repetitive surge peak on-state current	full cycle, $T_j$ initial= $25^\circ\text{C}$	F=50Hz t=20ms	-	80	A
			F=60Hz t=16.7ms	-	84	A
$I^2t$	$I^2t$ value for fusing	tp=10ms		-	36	$\text{A}^2\text{S}$
$di/dt$	Critical rate of rise of on-state current	$I_G=2x I_{GT}$ , tr<=100ns	F=120Hz $T_j=125^\circ\text{C}$	-	50	$\text{A}/\mu\text{s}$
$I_{GM}$	Peak gate current		tp=20us $T_j=125^\circ\text{C}$	-	4	A
$I_{DRM}$ $I_{RRM}$	$V_{DRM}=V_{RRM}$	$T_j=25^\circ\text{C}$		-	5	$\mu\text{A}$
		$T_j=125^\circ\text{C}$		-	1	mA
$P_{G(AV)}$	Average gate power dissipation	$T_j=125^\circ\text{C}$		-	1	W
$T_{stg}$	Storage junction temperature range			-40	150	$^\circ\text{C}$
$T_j$	Operating junction temperature range			-40	125	$^\circ\text{C}$

$T_j=25^\circ\text{C}$  unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT	
Static characteristics							
$I_{GT}(1)$ $V_{GT}$		$V_D=12\text{V}$ ; $R_L=30\Omega$	I-II-III	-	-	10	mA
			I-II-III	-	-	1.3	V
$I_L$		$I_G=1.2 I_{GT}$	I-III	-	-	25	mA
			II	-	-	30	mA
$I_H(2)$		$I_T=100\text{mA}$	-	-	15	mA	
$V_{GD}$		$V_D=V_{DRM}$ $R_L=3.3\text{K}\Omega$ $T_j=125^\circ\text{C}$	I-II-III	0.2	-	-	V
$dV/dt(2)$		$V_D=67\%V_{DRM}$ gate open; $T_j=125^\circ\text{C}$		40	-	-	$\text{V}/\mu\text{s}$
$(di/dt)c(2)$		$(dv/dt)c=0.1\text{V}/\mu\text{S}$ $T_j=125^\circ\text{C}$ $(dv/dt)c=10\text{V}/\mu\text{S}$ $T_j=125^\circ\text{C}$		5.4	-	-	$\text{V}/\mu\text{s}$
				2.8	-	-	

### Dynamic Characteristics

$V_{TM}(2)$	$I_{TM}=11\text{A}$ tp=380 $\mu\text{s}$	$T_j=25^\circ\text{C}$	-	-	1.55	V
$V_{to}(2)$ $R_d(2)$	Threshold voltage Dynamic resistance	$T_j=125^\circ\text{C}$ $T_j=125^\circ\text{C}$	-	-	0.85 50	V $\text{m}\Omega$

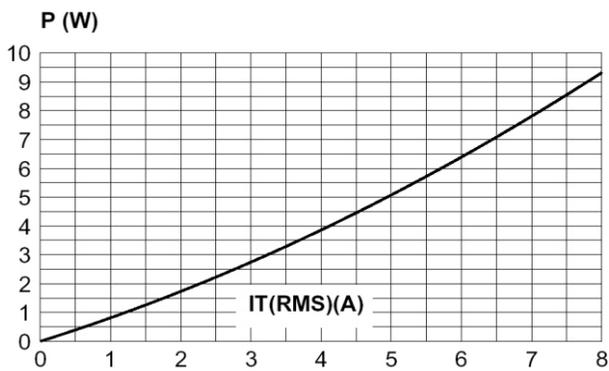
Note1: minimum  $I_{GT}$  is guaranteed at 5% of  $I_{GT}$  max.

Note2: for both polarities of A2 referenced to A1.

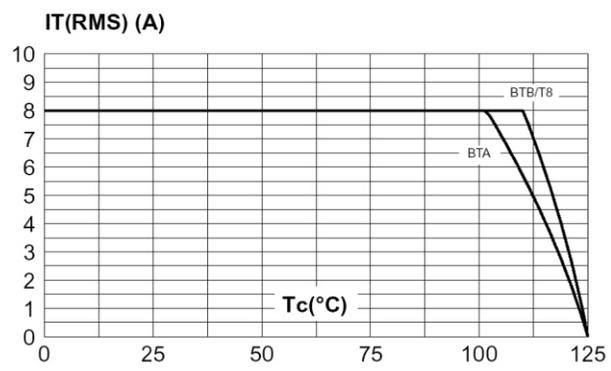
### HAOPIN MICROELECTRONICS CO.,LTD.

#### Description

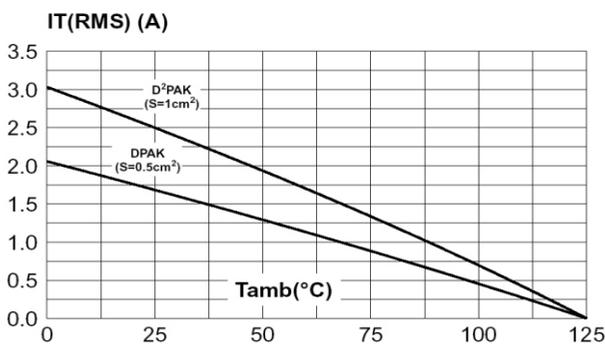
**Fig. 1:** Maximum power dissipation versus RMS on-state current (full cycle).



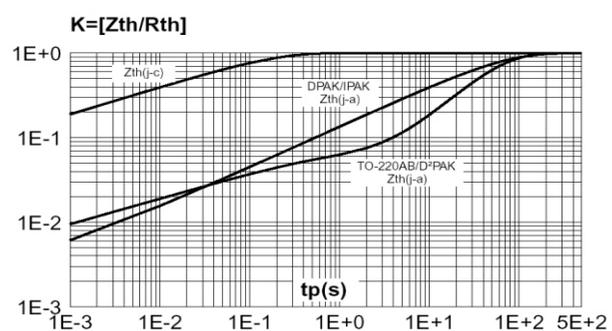
**Fig. 2-1:** RMS on-state current versus case temperature (full cycle).



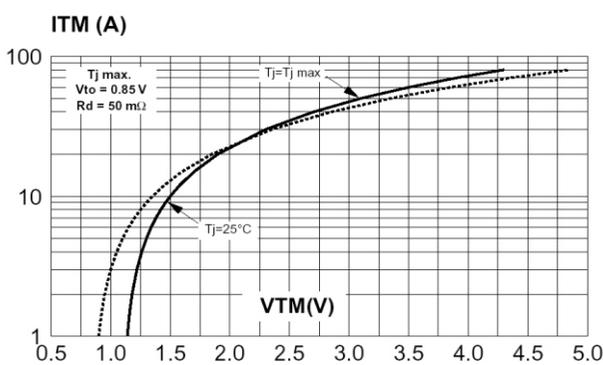
**Fig. 2-2:** RMS on-state current versus ambient temperature (printed circuit board FR4, copper thickness: 35µm), full cycle.



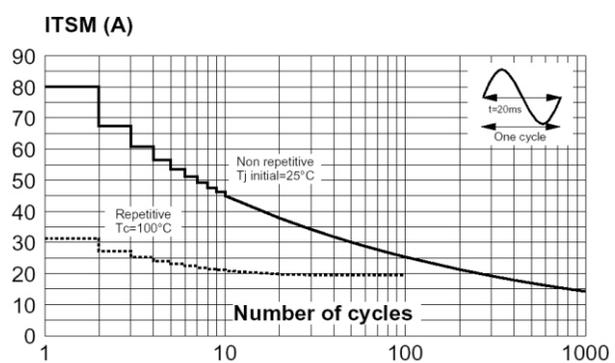
**Fig. 3:** Relative variation of thermal impedance versus pulse duration.



**Fig. 4:** On-state characteristics (maximum values).

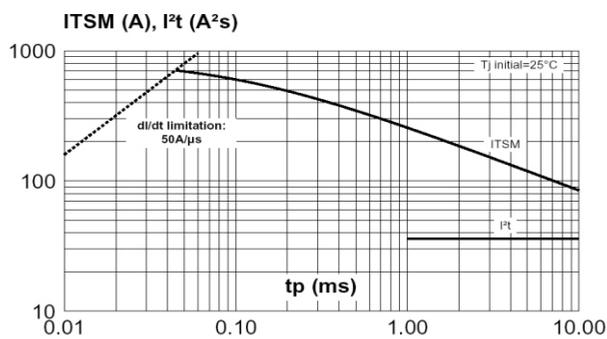


**Fig. 5:** Surge peak on-state current versus number of cycles.

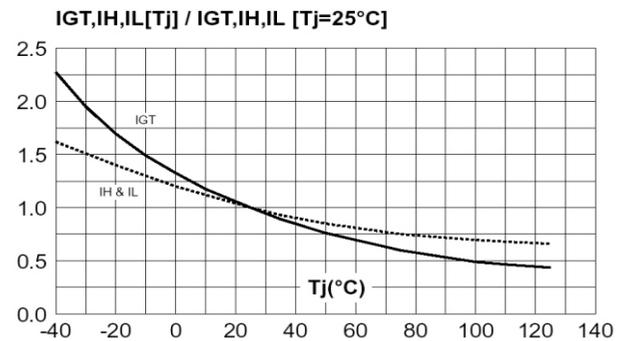


#### Description

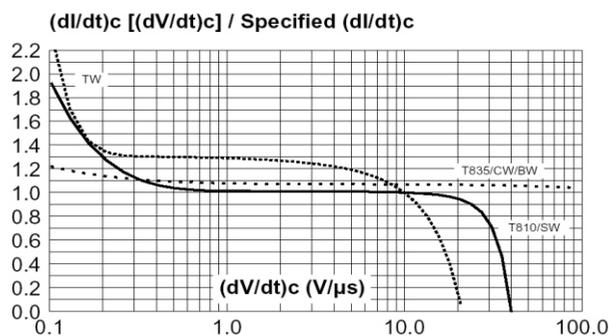
**Fig. 6:** Non-repetitive surge peak on-state current for a sinusoidal pulse with width  $t_p < 10\text{ms}$ , and corresponding value of  $I^2t$ .



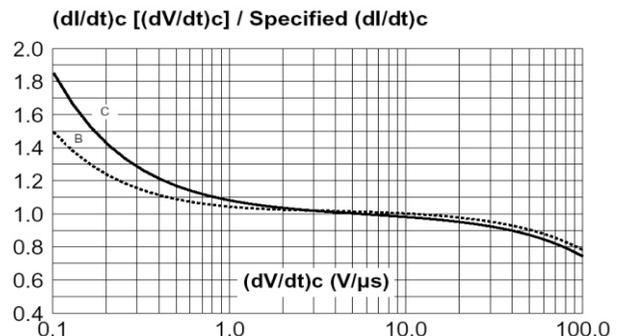
**Fig. 7:** Relative variation of gate trigger current, holding current and latching current versus junction temperature (typical values).



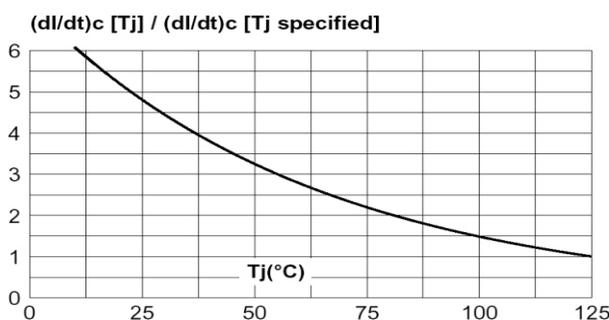
**Fig. 8-1:** Relative variation of critical rate of decrease of main current versus  $(dV/dt)_c$  (typical values). Snubberless & Logic Level Types



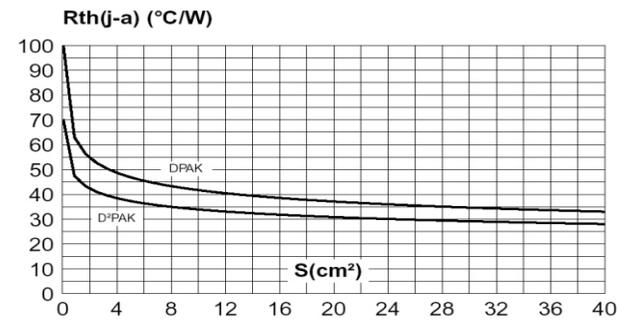
**Fig. 8-2:** Relative variation of critical rate of decrease of main current versus  $(dV/dt)_c$  (typical values). Standard Types



**Fig. 9:** Relative variation of critical rate of decrease of main current versus junction temperature.



**Fig. 10:** DPAK and D<sup>2</sup>PAK Thermal resistance junction to ambient versus copper surface under tab (printed circuit board FR4, copper thickness: 35 µm).





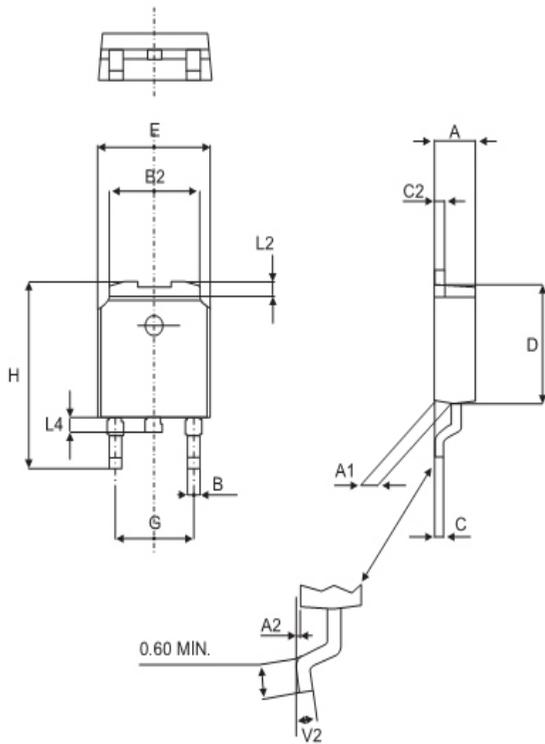
# HP8Q80DS

Three quadrant triacs

HAOPIN MICROELECTRONICS CO.,LTD.

## MECHANICAL DATA

Dimensions in mm  
 Net Mass: 0.3 g  
 TO-252



REF.	DIMENSIONS			
	Millimeters		Inches	
	Min.	Max	Min.	Max.
A	2.20	2.40	0.086	0.094
A1	0.90	1.10	0.035	0.043
A2	0.03	0.23	0.001	0.009
B	0.64	0.90	0.025	0.035
B2	5.20	5.40	0.204	0.212
C	0.45	0.60	0.017	0.023
C2	0.48	0.60	0.018	0.023
D	6.00	6.20	0.236	0.244
E	6.40	6.60	0.251	0.259
G	4.40	4.60	0.173	0.181
H	9.35	10.10	0.368	0.397
L2	0.80 typ.		0.031 typ.	
L4	0.60	1.00	0.023	0.039
R	0.2 typ.		0.007 typ.	
V2	0°	8°	0°	8°